Morphological Evaluation of Semiconductor Materials Using TEM

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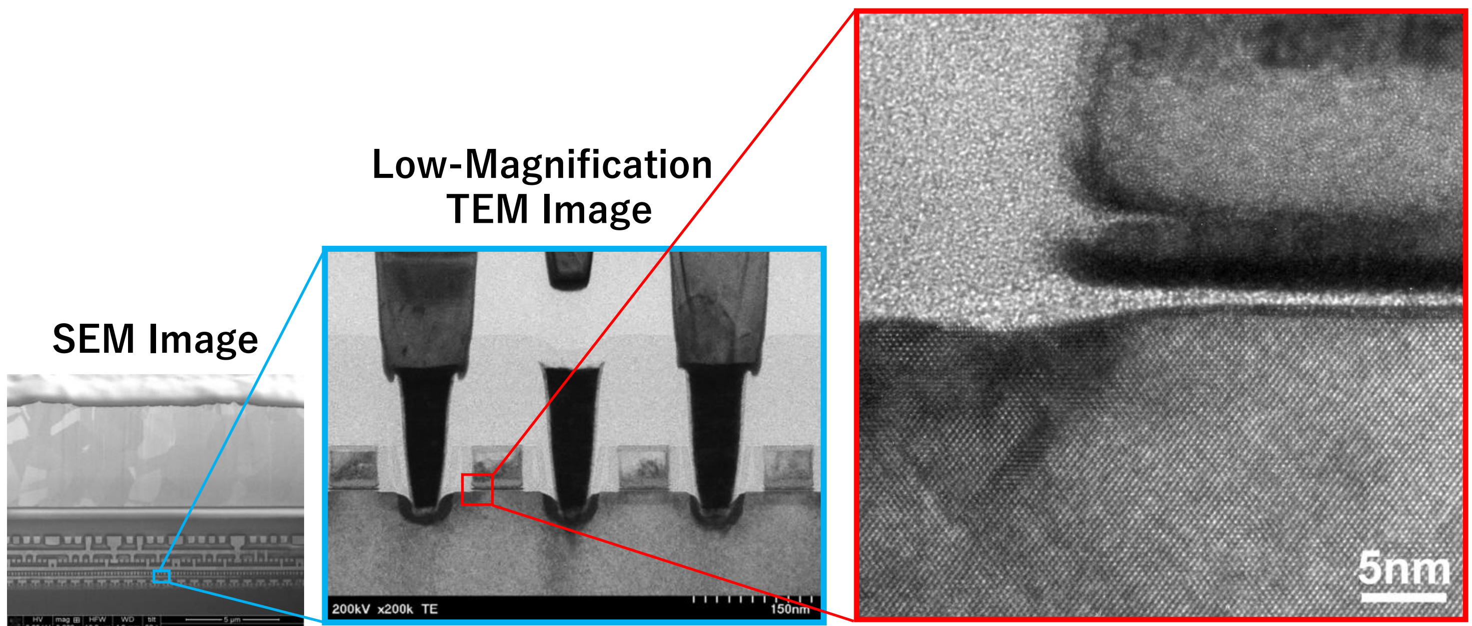
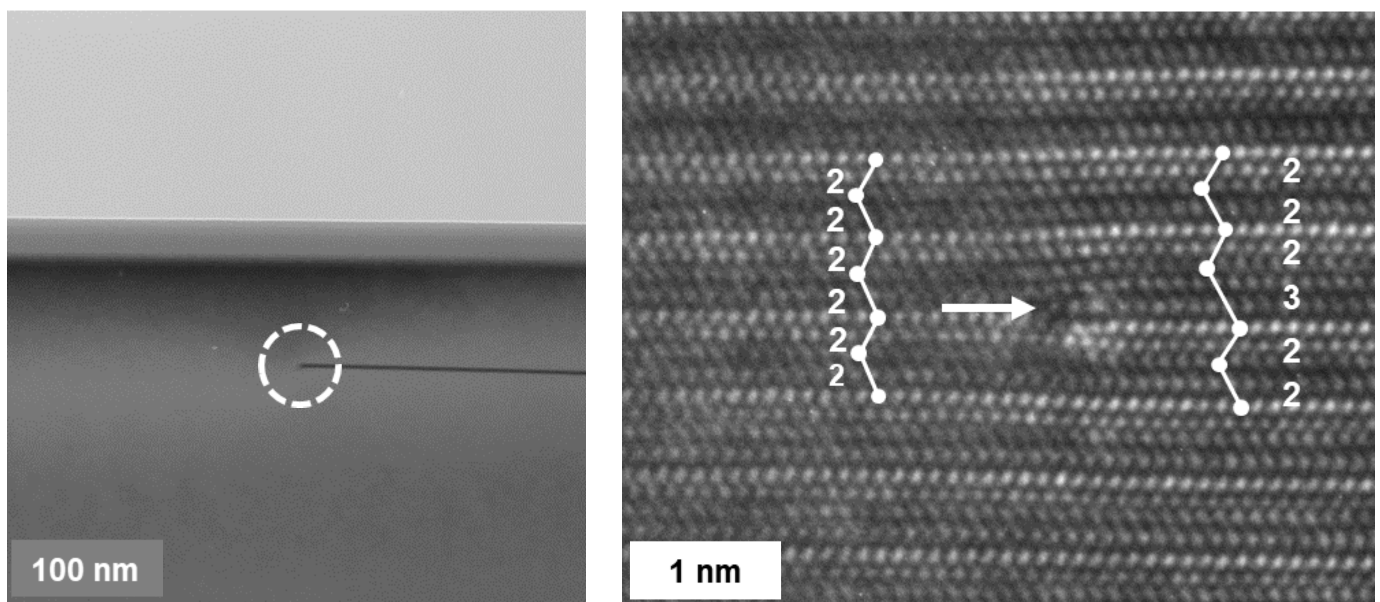
Structural Observation by TEM

<Features>
A TEM (Transmission Electron Microscope) is an instrument capable of observing extremely fine structures at high resolution. It allows structural observation on a sub-nanometer scale, thickness evaluation of thin films, as well as observation and structural analysis of defects in semiconductor crystal substrates.



Diffraction Conditions of Stacking Faults in SiC Epitaxial Layers・High-Resolution Observation and Analysis



※Source：M.Aoki, H.Kawanowa, G Feng, T Kimoto Jpn.J.Appl.Phys.52(2013)061301

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